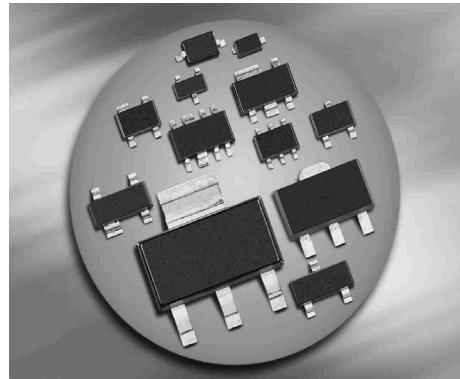


Silicon N_Channel MOSFET Tetrode

- Short-channel transistor with high S / C quality factor
- For low-noise, gain-controlled input stage up to 1 GHz
- Pb-free (RoHS compliant) package



ESD (Electrostatic discharge) sensitive device, observe handling precaution!

Type	Package	Pin Configuration						Marking
BF998	SOT143	1=S	2=D	3=G2	4=G1	-	-	MOs
BF998R	SOT143R	1=D	2=S	3=G1	4=G2	-	-	MRs

Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	12	V
Continuous drain current	I_D	30	mA
Gate 1/ gate 2-source current	$\pm I_{G1/2SM}$	10	
Total power dissipation	P_{tot}	200	
$T_S \leq 76 \text{ }^{\circ}\text{C}$, BF998, BF998R			
Storage temperature	T_{Stg}	-55 ... 150	$^{\circ}\text{C}$
Channel temperature	T_{ch}	150	

Thermal Resistance

Parameter	Symbol	Value	Unit
Channel - soldering point ¹⁾ , BF998, BF998R	R_{thchs}	≤ 370	K/W

¹For calculation of R_{thJA} please refer to Application Note AN077 (Thermal Resistance Calculation)

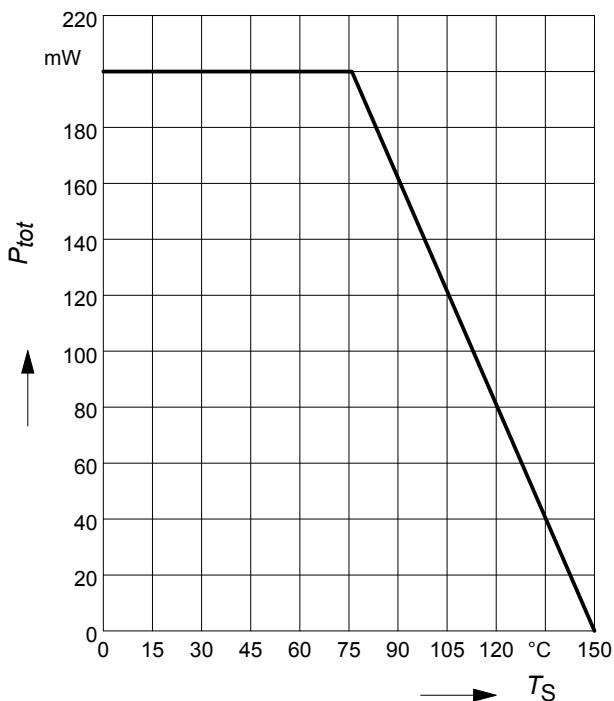
Electrical Characteristics at $T_A = 25^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
DC Characteristics					
Drain-source breakdown voltage $I_D = 10 \mu\text{A}, V_{G1S} = -4 \text{ V}, V_{G2S} = -4 \text{ V}$	$V_{(\text{BR})\text{DS}}$	12	-	-	V
Gate 1 source breakdown voltage $\pm I_{G2S} = 10 \text{ mA}, V_{G2S} = V_{\text{DS}} = 0$	$\pm V_{(\text{BR})\text{G1SS}}$	8	-	12	
Gate2 source breakdown voltage $\pm I_{G2S} = 10 \text{ mA}, V_{G2S} = V_{\text{DS}} = 0$	$\pm V_{(\text{BR})\text{G2SS}}$	8	-	12	
Gate 1 source leakage current $\pm V_{G1S} = 5 \text{ V}, V_{G2S} = V_{\text{DS}} = 0$	$\pm I_{\text{G1SS}}$	-	-	50	nA
Gate 2 source leakage current $\pm V_{G2S} = 5 \text{ V}, V_{G2S} = V_{\text{DS}} = 0$	$\pm I_{\text{G2SS}}$	-	-	50	nA
Drain current $V_{\text{DS}} = 8 \text{ V}, V_{G1S} = 0, V_{G2S} = 4 \text{ V}$	I_{DSS}	5	9	15	mA
Gate 1 source pinch-off voltage $V_{\text{DS}} = 8 \text{ V}, V_{G2S} = 4 \text{ V}, I_D = 20 \mu\text{A}$	$-V_{\text{G1S(p)}}$	-	0.8	2.5	V
Gate 2 source pinch-off voltage $V_{\text{DS}} = 8 \text{ V}, V_{G1S} = 0, I_D = 20 \mu\text{A}$	$-V_{\text{G2S(p)}}$	-	0.8	2	

Electrical Characteristics at $T_A = 25^\circ\text{C}$, unless otherwise specified

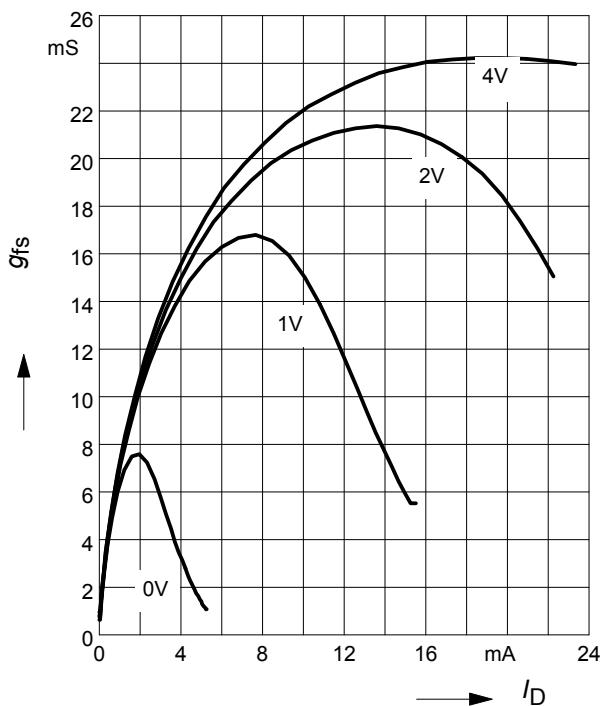
Parameter	Symbol	Values			Unit
		min.	typ.	max.	
AC Characteristics (verified by random sampling)					
Forward transconductance $V_{DS} = 8 \text{ V}, I_D = 10 \text{ mA}, V_{G2S} = 4 \text{ V}$	g_{fs}	20	24	-	-
Gate 1 input capacitance $V_{DS} = 8 \text{ V}, I_D = 10 \text{ mA}, V_{G2S} = 4 \text{ V}, f = 10 \text{ MHz}$	C_{g1ss}	-	2.1	2.5	pF
Gate 2 input capacitance $V_{DS} = 8 \text{ V}, I_D = 10 \text{ mA}, V_{G2S} = 4 \text{ V}, f = 10 \text{ MHz}$	C_{g2ss}	-	1.2	-	pF
Feedback capacitance $V_{DS} = 8 \text{ V}, I_D = 10 \text{ mA}, V_{G2S} = 4 \text{ V}, f = 10 \text{ MHz}$	C_{dg1}	-	25	-	fF
Output capacitance $V_{DS} = 8 \text{ V}, I_D = 10 \text{ mA}, V_{G2S} = 4 \text{ V}, f = 10 \text{ MHz}$	C_{dss}	-	1.1	-	pF
Power gain $V_{DS} = 8 \text{ V}, I_D = 10 \text{ mA}, V_{G2S} = 4 \text{ V}, f = 45 \text{ MHz}$ $V_{DS} = 8 \text{ V}, I_D = 10 \text{ mA}, V_{G2S} = 4 \text{ V}, f = 800 \text{ MHz}$	G_p	-	28	-	dB
-	-	-	20	-	
Noise figure $V_{DS} = 8 \text{ V}, I_D = 10 \text{ mA}, V_{G2S} = 4 \text{ V}, f = 45 \text{ MHz}$ $V_{DS} = 8 \text{ V}, I_D = 10 \text{ mA}, V_{G2S} = 4 \text{ V}, f = 800 \text{ MHz}$	F	-	2.8	-	dB
-	-	-	1.8	-	
Gain control range $V_{DS} = 8 \text{ V}, V_{G2S} = 4 \dots -2 \text{ V}, f = 800 \text{ MHz}$	ΔG_p	40	50	-	

Total power dissipation $P_{\text{tot}} = f(T_S)$
BF998, BF998R

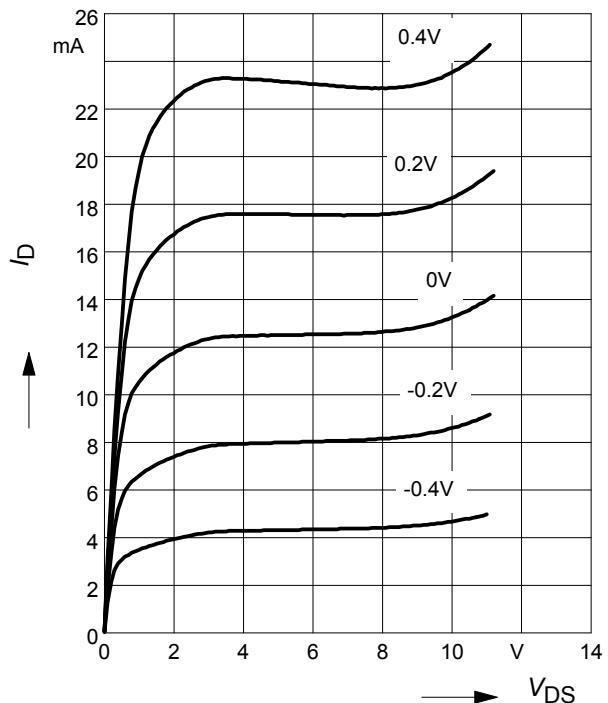


Gate 1 forward transconductance

$g_{fs} = f(I_D)$
 $V_{DS} = 5V$, V_{G2S} = Parameter

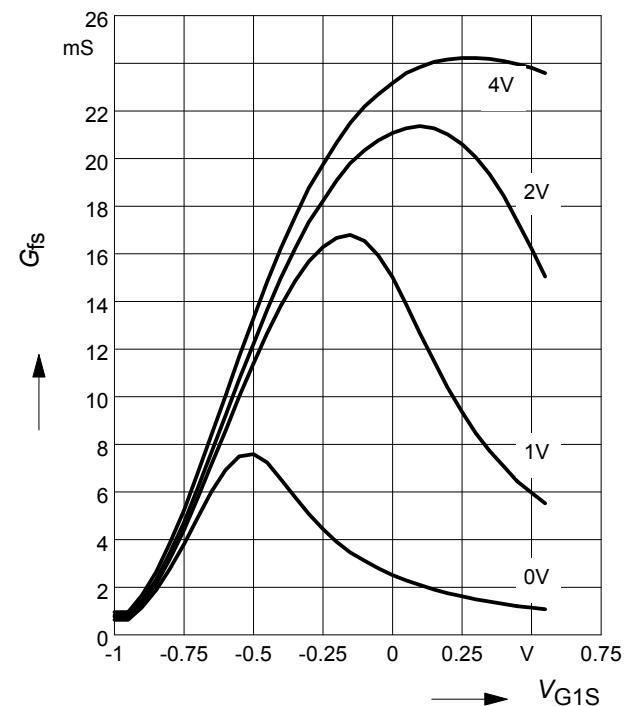


Output characteristics $I_D = f(V_{DS})$
 $V_{G2S} = 4V$
 V_{G1S} = Parameter



Gate 1 forward transconductance

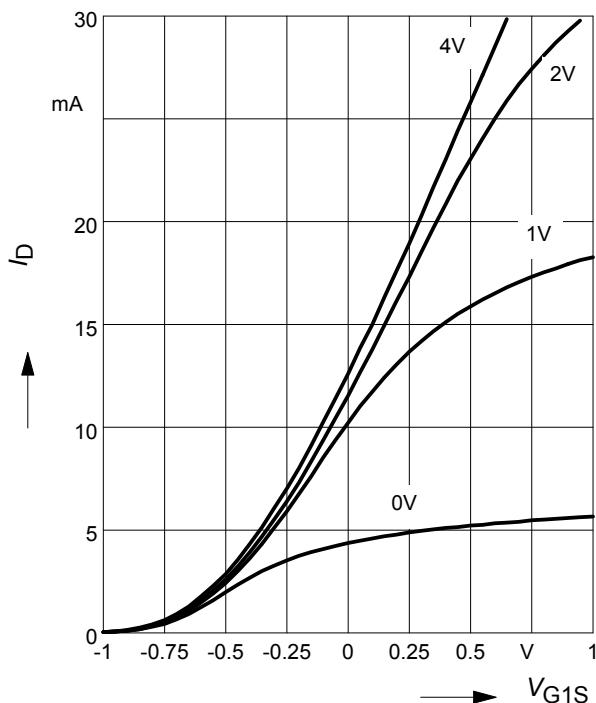
$g_{fs1} = f(V_{G1S})$



Drain current $I_D = f(V_{G1S})$

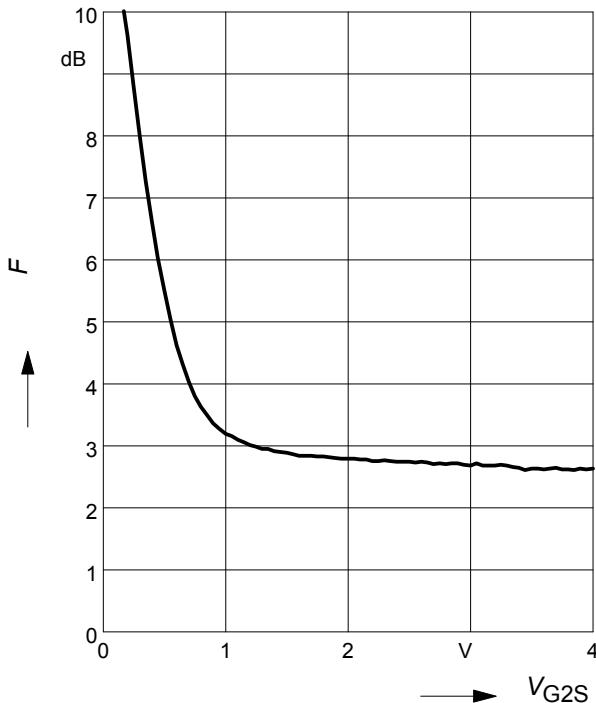
$V_{DS} = 5V$

V_{G2S} = Parameter



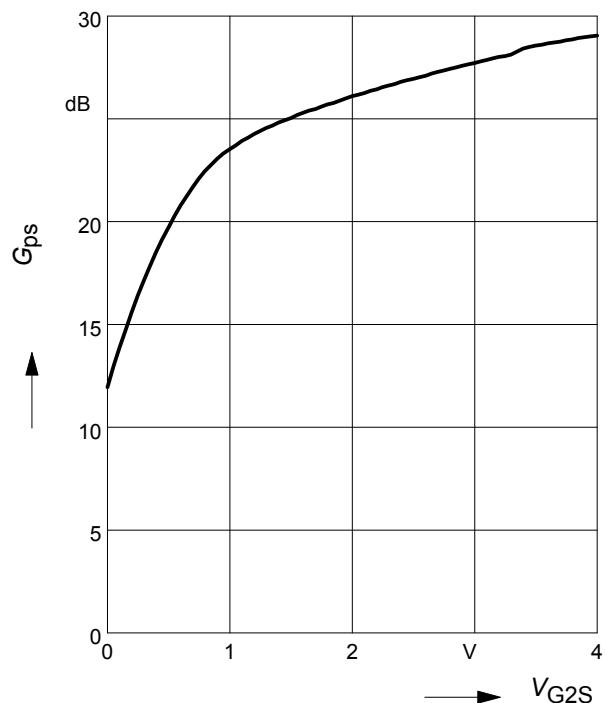
Noise figure $F = f(V_{G2S})$

$f = 45 \text{ MHz}$



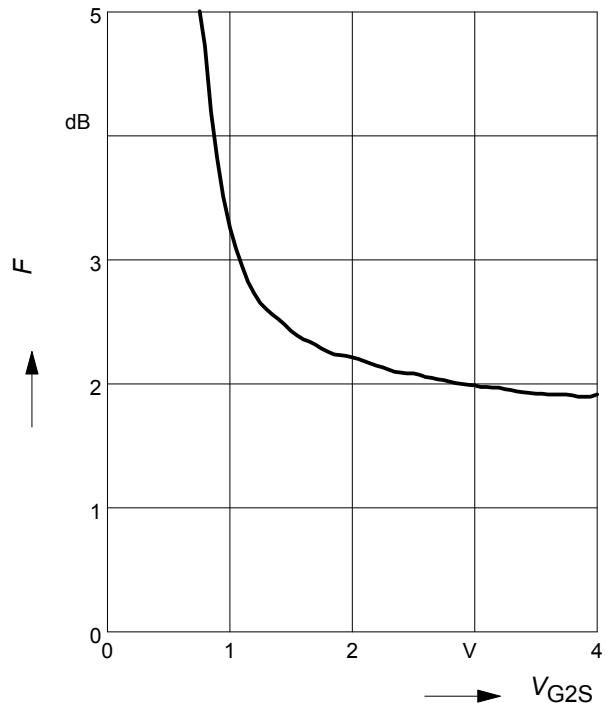
Power gain $G_{ps} = f(V_{G2S})$

$f = 45 \text{ MHz}$

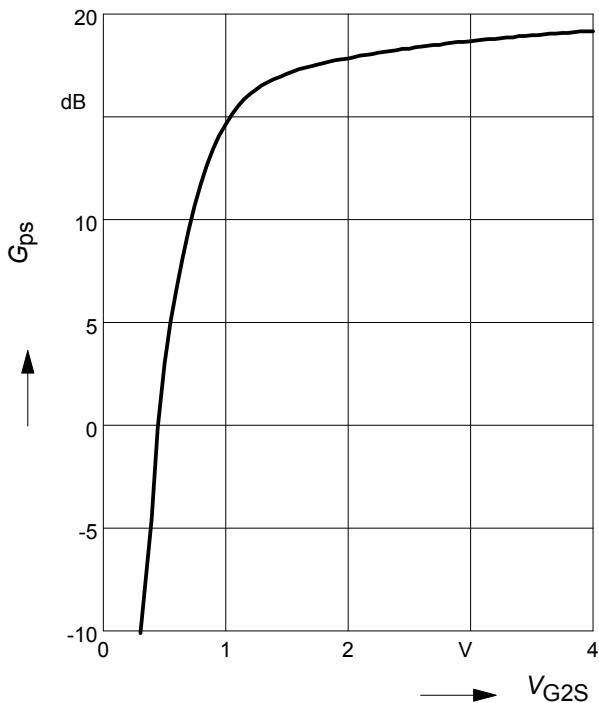


Noise figure $F = f(V_{G2S})$

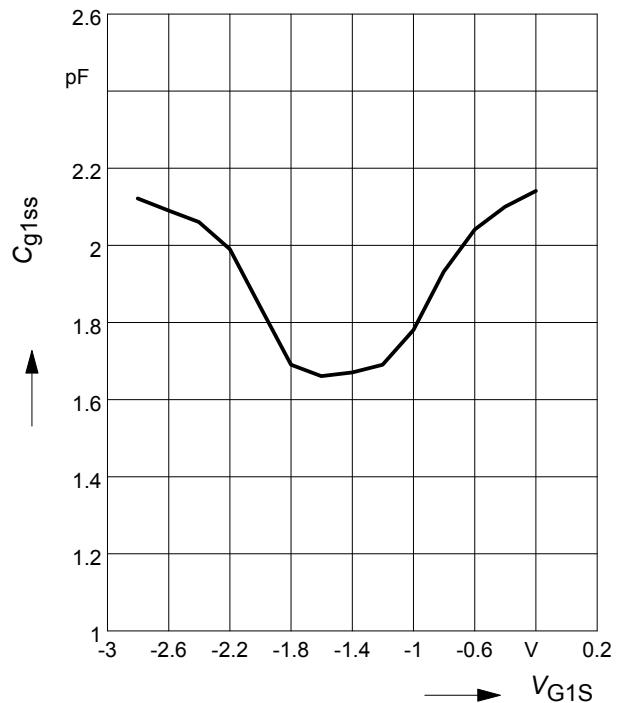
$f = 800 \text{ MHz}$



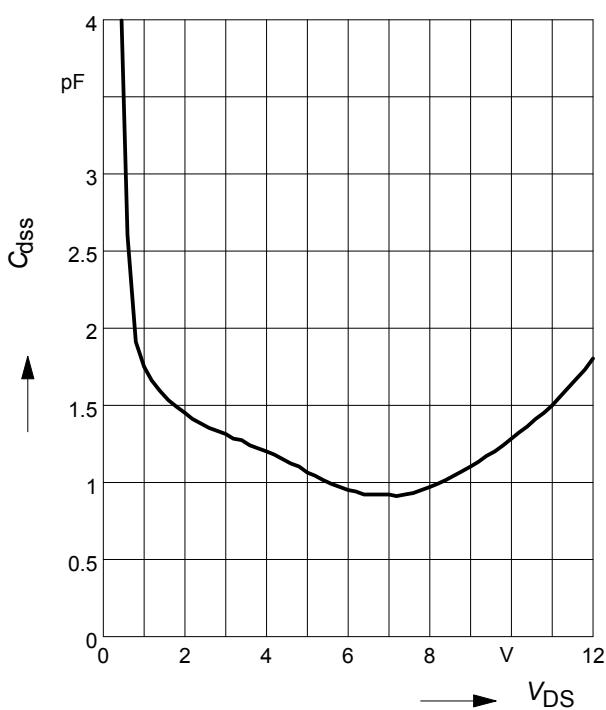
Power gain $G_{ps} = f(V_{G2S})$
 $f = 800 \text{ MHz}$



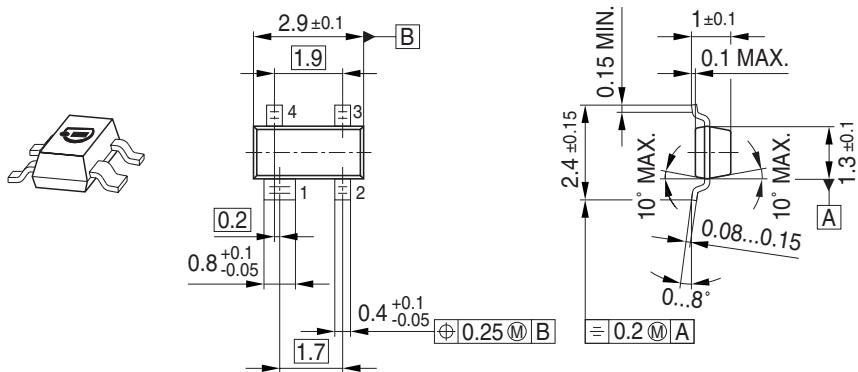
Gate 1 input capacitance $C_{g1ss} = f(V_{G1S})$



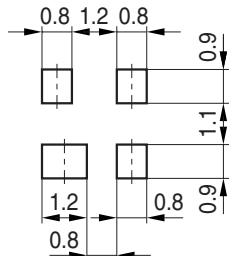
Output capacitance $C_{dss} = f(V_{DS})$



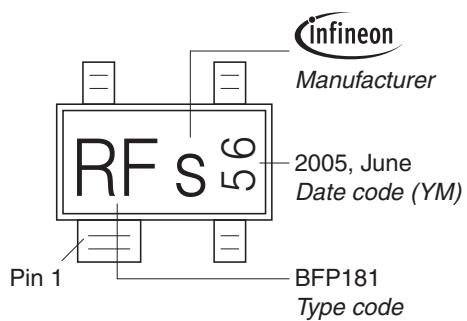
Package Outline



Foot Print

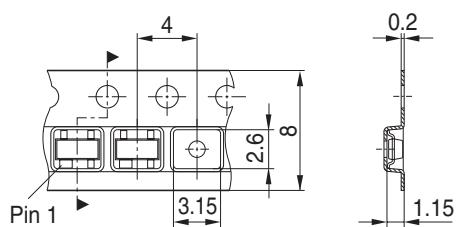


Marking Layout (Example)

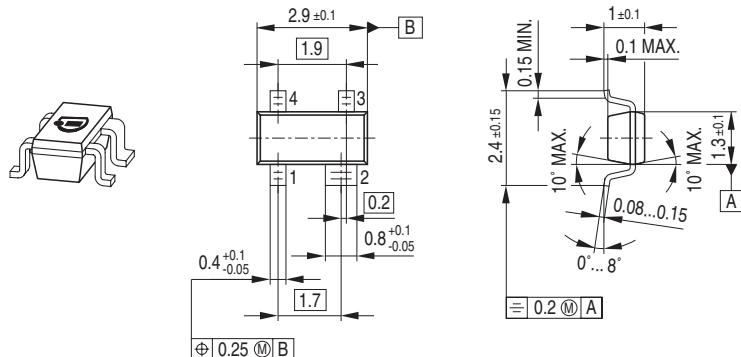


Standard Packing

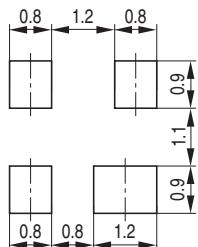
Reel ø180 mm = 3.000 Pieces/Reel
 Reel ø330 mm = 10.000 Pieces/Reel



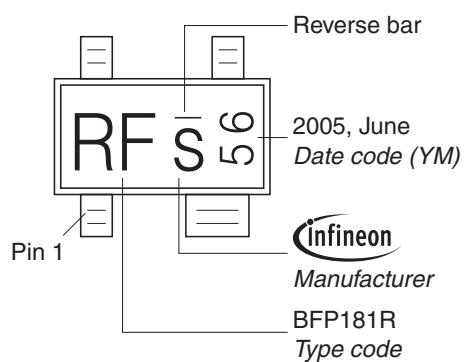
Package Outline



Foot Print

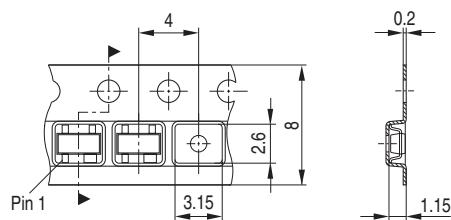


Marking Layout (Example)



Standard Packing

Reel ø180 mm = 3.000 Pieces/Reel
 Reel ø330 mm = 10.000 Pieces/Reel



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